

<b>Notice of References Cited</b>	Application/Control No. 10/594,997		Applicant(s)/Patent Under Reexamination ITOH ET AL.	
	Examiner HENRY S. HU		Art Unit 1764	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,038,004 B2	05-2006	Chen et al.	528/86
*	B	US-5,114,809	05-1992	Nakacho et al.	429/315
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	CN-1385464 A	12-2002	CN	Cui, Wei	-----
*	O	JP-2004-087137	03-2004	JP	Kamiyama, Koji	-----
*	P	WO-02-92638 A1	11-2002	WO	Cui, Wei	-----
*	Q	CN-2005-80012249.3	02-2009	CN	Itoh et al.	-----
*	R	KR-2008-003475317	01-2008	KR	(Korean abstract only)	-----
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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